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SiC JFET Division

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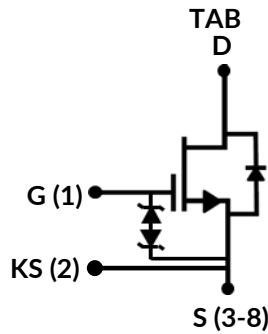
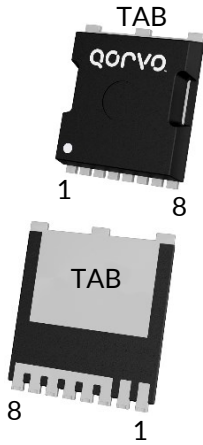
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DATASHEET

UJ4SC075010L8S



Silicon Carbide (SiC) Cascode JFET - EliteSiC, Power N-Channel, TOLL, 750V, 10.7 mohm

Rev. C, January 2025

Description

The UJ4SC075010L8S is a 750V, 10.7mΩ G4 SiC FET. It is based on a unique ‘cascode’ circuit configuration, in which a normally-on SiC JFET is co-packaged with a Si MOSFET to produce a normally-off SiC FET device. The device’s standard gate-drive characteristics allows use of off-the-shelf gate drivers hence requiring minimal re-design when replacing Si IGBTs, Si superjunction devices or SiC MOSFETs. Available in the space-saving MO-229 package which enables automated assembly, this device exhibits ultra-low gate charge and exceptional reverse recovery characteristics, making it ideal for switching inductive loads and any application requiring standard gate drive.

Features

- ◆ On-resistance $R_{DS(on)}$: 10.7mΩ (typ)
- ◆ Operating temperature: 175°C (max)
- ◆ Excellent reverse recovery: $Q_{rr} = 274nC$
- ◆ Low body diode V_{FSD} : 1.1V
- ◆ Low gate charge: $Q_G = 75nC$
- ◆ Threshold voltage $V_{G(th)}$: 4.5V (typ) allowing 0 to 15V drive
- ◆ Low intrinsic capacitance
- ◆ ESD protected, HBM class 2
- ◆ MO-229 packaging for faster switching, clean gate waveforms

Typical applications

- ◆ Solid state relays and circuit-breakers
- ◆ Line rectification and active-bridge rectification circuits in AC/DC front-ends
- ◆ EV charging
- ◆ PV inverters
- ◆ Switch mode power supplies
- ◆ Power factor correction modules
- ◆ Motor drives
- ◆ Induction heating

Part Number	Package	Marking
UJ4SC075010L8S	MO-229	UJ4SC075010L8S



Maximum Ratings

Parameter	Symbol	Test Conditions	Value	Units
Drain-source voltage	V_{DS}		750	V
Gate-source voltage	V_{GS}	DC	-20 to +20	V
		AC (f > 1Hz)	-25 to +25	V
Continuous drain current ¹	I_D	$T_C < 75^\circ\text{C}$	106	A
		$T_C = 100^\circ\text{C}$	92	A
Pulsed drain current ²	I_{DM}	$T_C = 25^\circ\text{C}$	300	A
Single pulsed avalanche energy ³	E_{AS}	L=15mH, $I_{AS} = 4.5\text{A}$	151	mJ
SiC FET dv/dt ruggedness	dv/dt	$V_{DS} [500\text{V}$	100	V/ns
Power dissipation	P_{tot}	$T_C = 25^\circ\text{C}$	556	W
Maximum junction temperature	$T_{J,max}$		175	$^\circ\text{C}$
Operating and storage temperature	T_J, T_{STG}		-55 to 175	$^\circ\text{C}$
Reflow soldering temperature	T_{solder}	reflow MSL 1	260	$^\circ\text{C}$

1. Limited by bondwires

2. Pulse width t_p limited by $T_{J,max}$

3. Starting $T_J = 25^\circ\text{C}$

Thermal Characteristics

Parameter	Symbol	Test Conditions	Value			Units
			Min	Typ	Max	
Thermal resistance, junction-to-case	$R_{\theta JC}$			0.21	0.27	$^\circ\text{C}/\text{W}$

Electrical Characteristics ($T_J = +25^\circ\text{C}$ unless otherwise specified)

Typical Performance - Static

Parameter	Symbol	Test Conditions	Value			Units
			Min	Typ	Max	
Drain-source breakdown voltage	BV_{DS}	$V_{GS}=0V, I_D=1mA$	750			V
Total drain leakage current	I_{DSS}	$V_{DS}=750V,$ $V_{GS}=0V, T_J=25^\circ\text{C}$		3.5	60	μA
		$V_{DS}=750V,$ $V_{GS}=0V, T_J=175^\circ\text{C}$		45		
Total gate leakage current	I_{GSS}	$V_{DS}=0V, T_J=25^\circ\text{C},$ $V_{GS}=-20V / +20V$		2	20	μA
Drain-source on-resistance	$R_{DS(on)}$	$V_{GS}=12V, I_D=60A,$ $T_J=25^\circ\text{C}$		10.7	14.2	m Ω
		$V_{GS}=12V, I_D=60A,$ $T_J=125^\circ\text{C}$		18.1		
		$V_{GS}=12V, I_D=60A,$ $T_J=175^\circ\text{C}$		24		
Gate threshold voltage	$V_{G(th)}$	$V_{DS}=5V, I_D=10mA$	3.5	4.5	5.5	V
Gate resistance	R_G	$f=1\text{MHz}, \text{open drain}$		2.3		Ω

Typical Performance - Reverse Diode

Parameter	Symbol	Test Conditions	Value			Units
			Min	Typ	Max	
Diode continuous forward current ¹	I_S	$T_C < 75^\circ\text{C}$			106	A
Diode pulse current ²	$I_{S,pulse}$	$T_C=25^\circ\text{C}$			300	A
Forward voltage	V_{FSD}	$V_{GS}=0V, I_S=30A,$ $T_J=25^\circ\text{C}$		1.1	1.24	V
		$V_{GS}=0V, I_S=30A,$ $T_J=175^\circ\text{C}$		1.2		
Reverse recovery charge	Q_{rr}	$V_{DS}=400V, I_S=60A,$ $V_{GS}=0V, R_G=30\Omega$		274		nC
Reverse recovery time	t_{rr}	$di/dt=2500A/\mu\text{s},$ $T_J=25^\circ\text{C}$		18.5		ns
Reverse recovery charge	Q_{rr}	$V_{DS}=400V, I_S=60A,$ $V_{GS}=0V, R_G=30\Omega$		290		nC
Reverse recovery time	t_{rr}	$di/dt=2500A/\mu\text{s},$ $T_J=150^\circ\text{C}$		20		ns

Typical Performance - Dynamic

Parameter	Symbol	Test Conditions	Value			Units	
			Min	Typ	Max		
Input capacitance	C_{iss}	$V_{DS}=400V, V_{GS}=0V$ $f=100kHz$		3245		pF	
Output capacitance	C_{oss}			178			
Reverse transfer capacitance	C_{rss}			1.2			
Effective output capacitance, energy related	$C_{oss(er)}$	$V_{DS}=0V$ to $400V$, $V_{GS}=0V$		225		pF	
Effective output capacitance, time related	$C_{oss(tr)}$	$V_{DS}=0V$ to $400V$, $V_{GS}=0V$		470		pF	
C_{OSS} stored energy	E_{oss}	$V_{DS}=400V, V_{GS}=0V$		18		μJ	
Total gate charge	Q_G	$V_{DS}=400V, I_D=60A$, $V_{GS} = -0V$ to $15V$		75		nC	
Gate-drain charge	Q_{GD}			13			
Gate-source charge	Q_{GS}			22			
Turn-on delay time	$t_{d(on)}$	Notes 4 and 5, $V_{DS}=400V, I_D=60A$, Gate Driver = $0V$ to $+15V$, Turn-on $R_{G,EXT}=1\Omega$, Turn-off $R_{G,EXT}=5\Omega$, inductive Load, FWD: same device with $V_{GS} = 0V$ and $R_G = 5\Omega$, RC snubber: $R_S=5\Omega$ and $C_S=440pF$, $T_J=25^\circ C$		17.6		ns	
Rise time	t_r			22.4			
Turn-off delay time	$t_{d(off)}$			65			
Fall time	t_f			12.8			
Turn-on energy including R_S energy	E_{ON}				173		μJ
Turn-off energy including R_S energy	E_{OFF}				132		
Total switching energy	E_{TOTAL}				305		
Snubber R_S energy during turn-on	E_{RS_ON}				11		
Snubber R_S energy during turn-off	E_{RS_OFF}				37		
Turn-on delay time	$t_{d(on)}$				18		
Rise time	t_r			25			
Turn-off delay time	$t_{d(off)}$			68			
Fall time	t_f			13.6			
Turn-on energy including R_S energy	E_{ON}			203		μJ	
Turn-off energy including R_S energy	E_{OFF}			145			
Total switching energy	E_{TOTAL}			348			
Snubber R_S energy during turn-on	E_{RS_ON}			11			
Snubber R_S energy during turn-off	E_{RS_OFF}			37			

4. Measured with the switching test circuit in Figure 26.

5. In this datasheet, all the switching energies (turn-on energy, turn-off energy and total energy) presented in the tables and Figures include the device RC snubber energy losses.

Typical Performance Diagrams

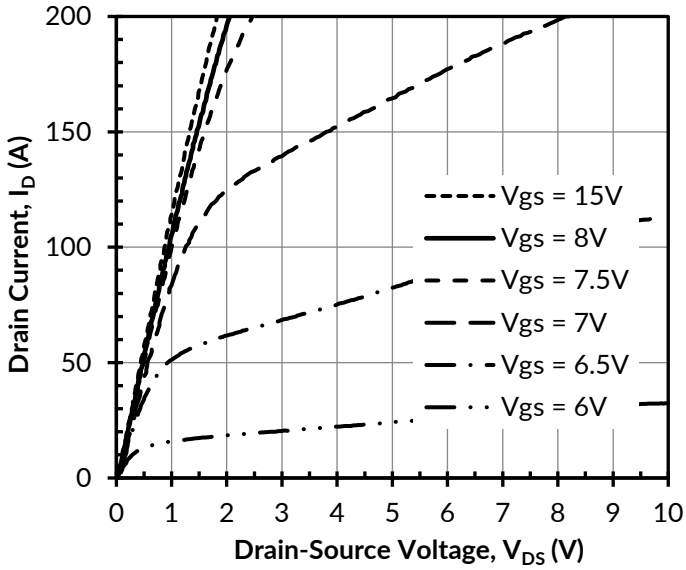


Figure 1. Typical output characteristics at $T_j = -55^\circ\text{C}$, $t_p < 250\mu\text{s}$

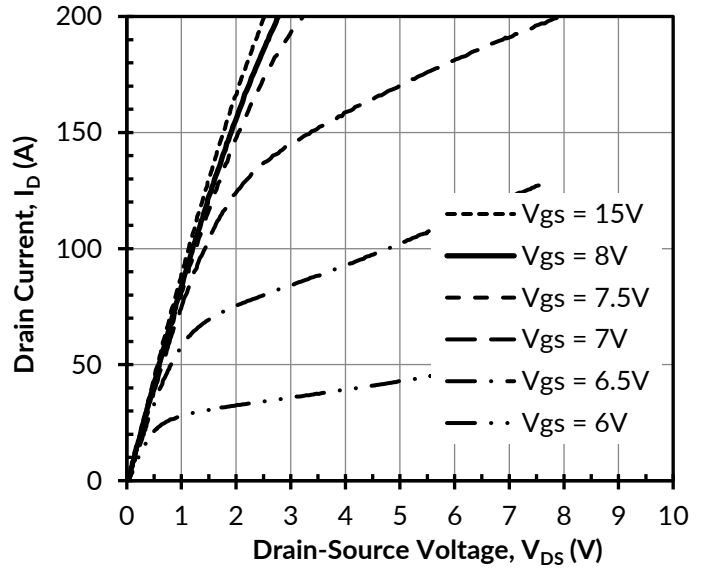


Figure 2. Typical output characteristics at $T_j = 25^\circ\text{C}$, $t_p < 250\mu\text{s}$

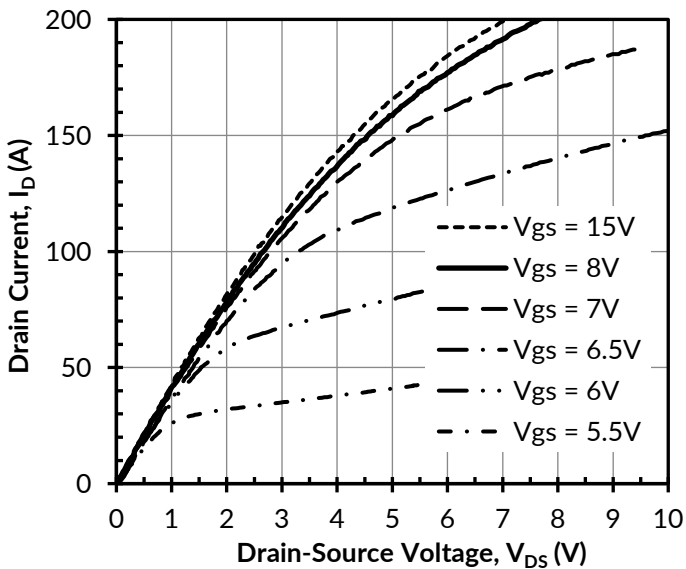


Figure 3. Typical output characteristics at $T_j = 175^\circ\text{C}$, $t_p < 250\mu\text{s}$

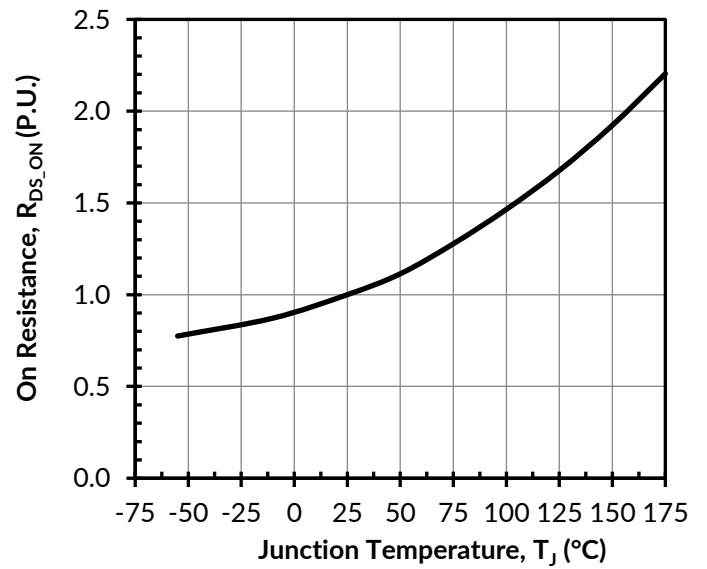


Figure 4. Normalized on-resistance vs. temperature at $V_{GS} = 12\text{V}$ and $I_D = 60\text{A}$

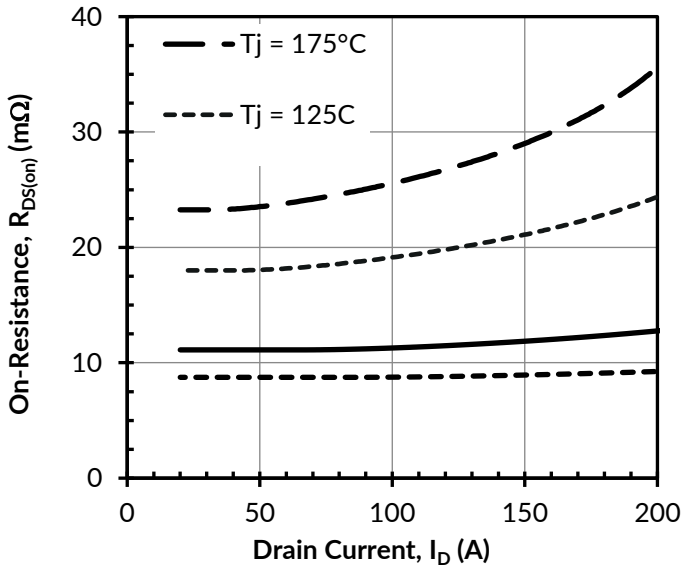


Figure 5. Typical drain-source on-resistances at $V_{GS} = 12V$

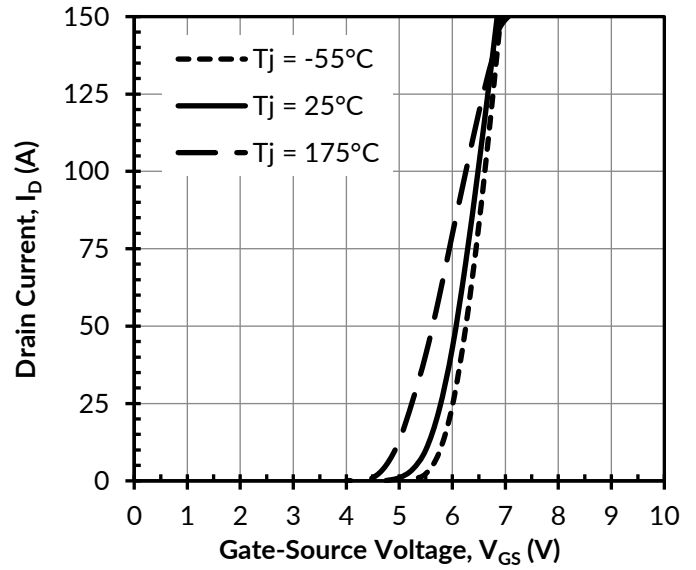


Figure 6. Typical transfer characteristics at $V_{DS} = 5V$

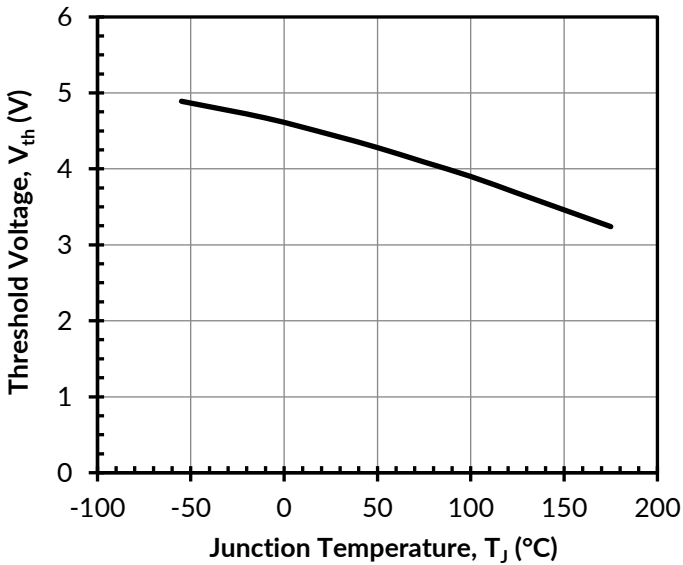


Figure 7. Threshold voltage vs. junction temperature at $V_{DS} = 5V$ and $I_D = 10mA$

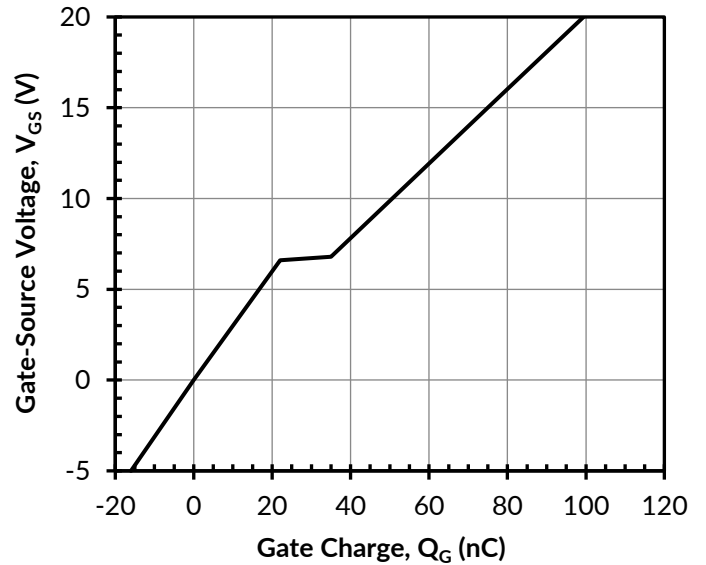


Figure 8. Typical gate charge at $I_D = 60A$

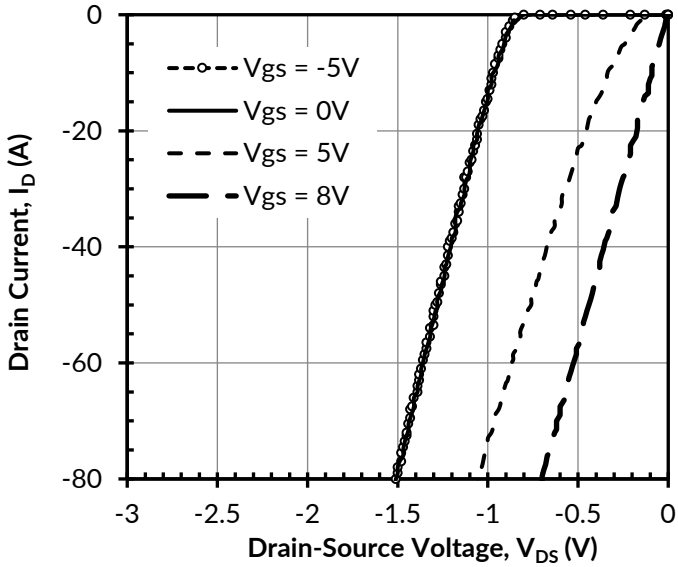


Figure 9. 3rd quadrant characteristics at $T_j = -55^\circ\text{C}$

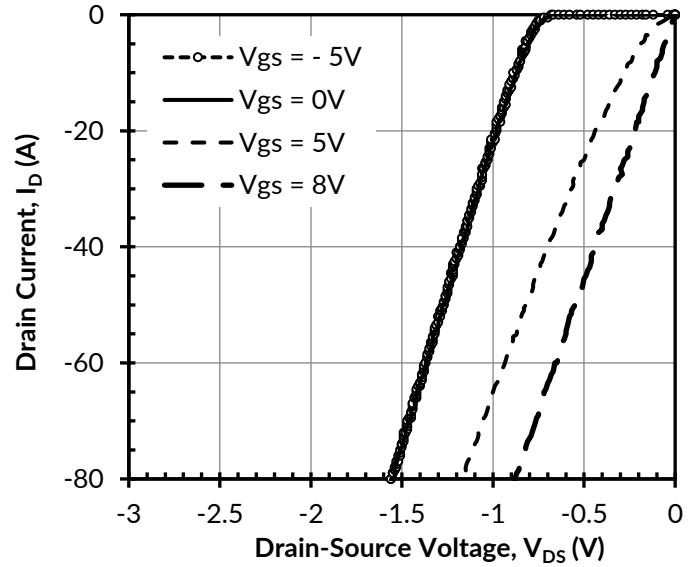


Figure 10. 3rd quadrant characteristics at $T_j = 25^\circ\text{C}$

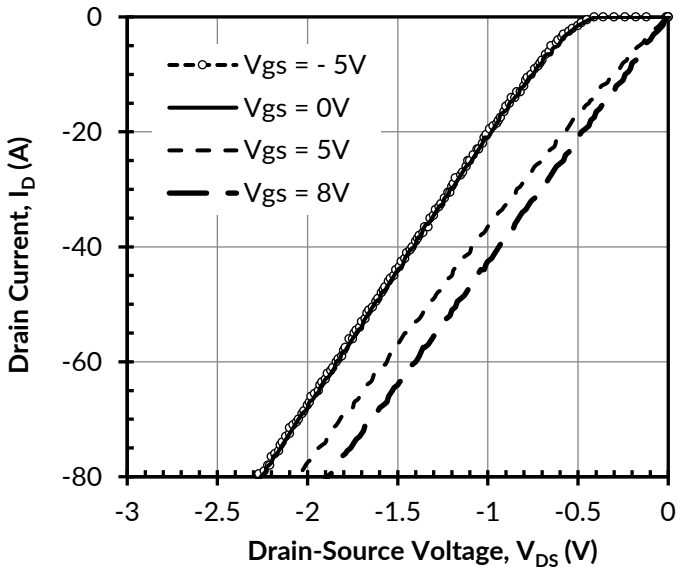


Figure 11. 3rd quadrant characteristics at $T_j = 175^\circ\text{C}$

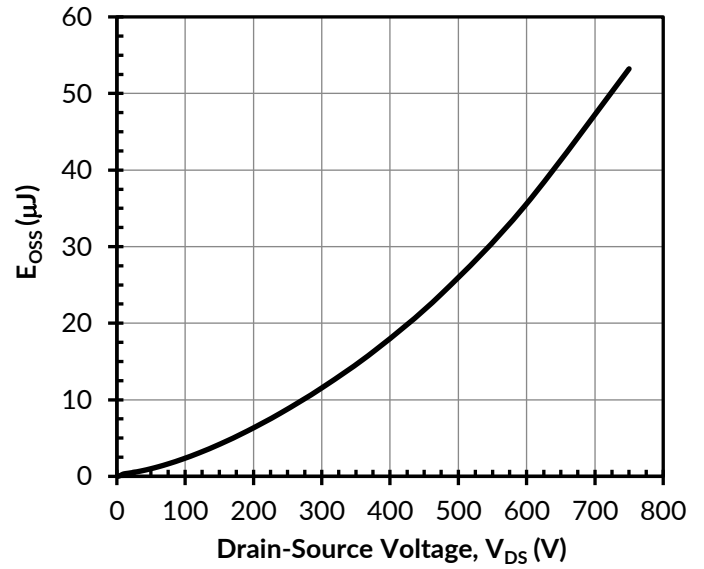


Figure 12. Typical stored energy in C_{OSS} at $V_{GS} = 0\text{V}$

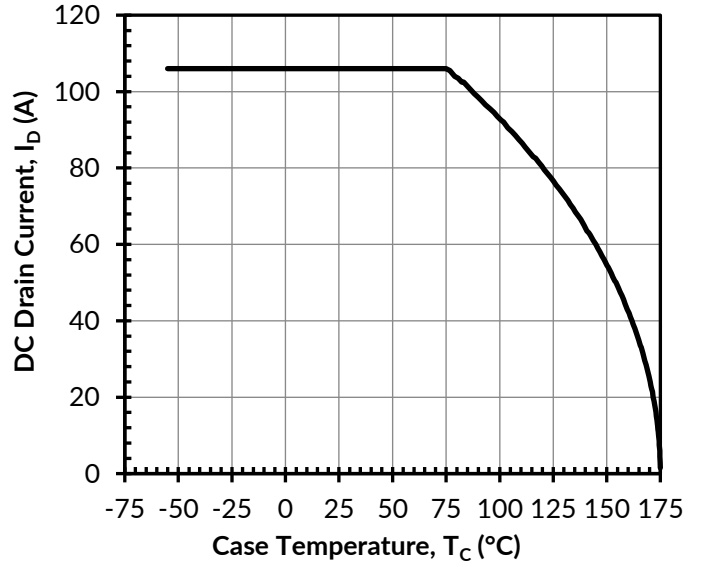
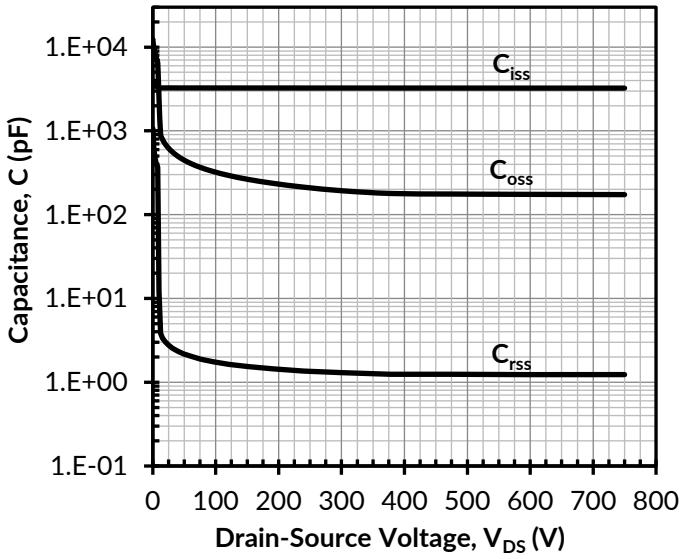


Figure 13. Typical capacitances at $f = 100\text{kHz}$ and $V_{GS} = 0\text{V}$ Figure 14. DC drain current derating

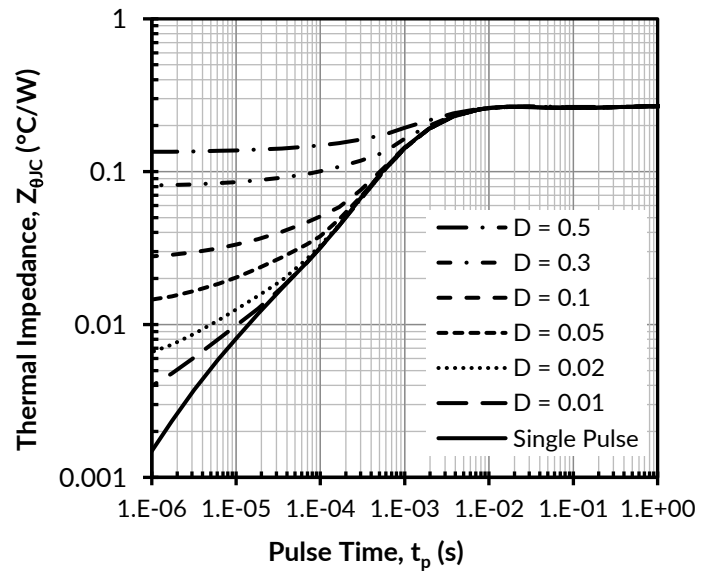
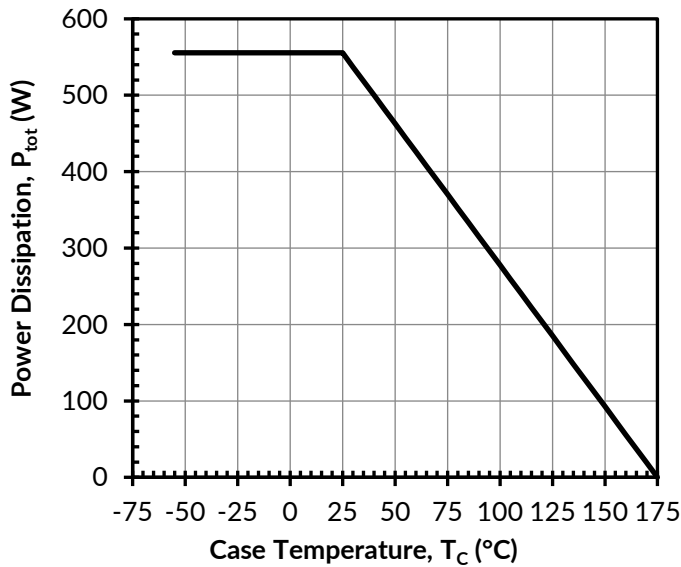


Figure 15. Total power dissipation

Figure 16. Maximum transient thermal impedance

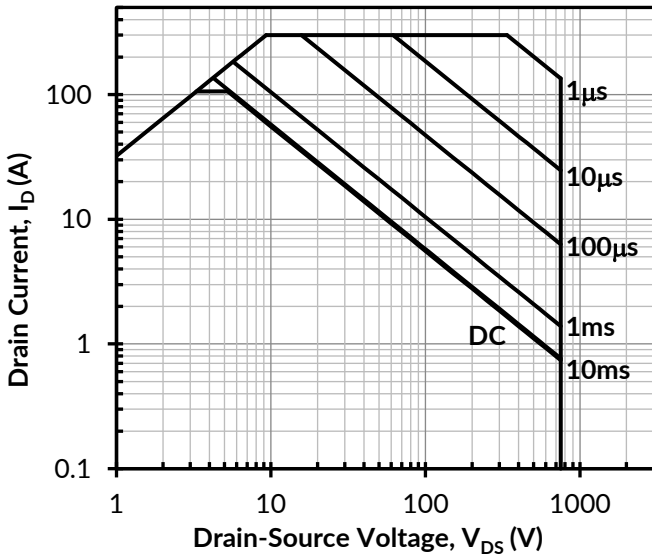


Figure 17. Safe operation area at $T_C = 25^\circ\text{C}$, $D = 0$, Parameter t_p

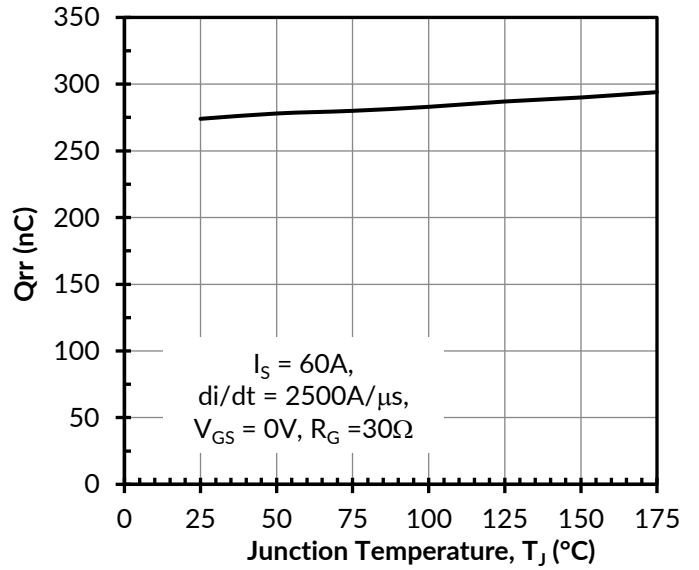


Figure 18. Reverse recovery charge Q_{rr} vs. junction temperature at $V_{DS} = 400\text{V}$

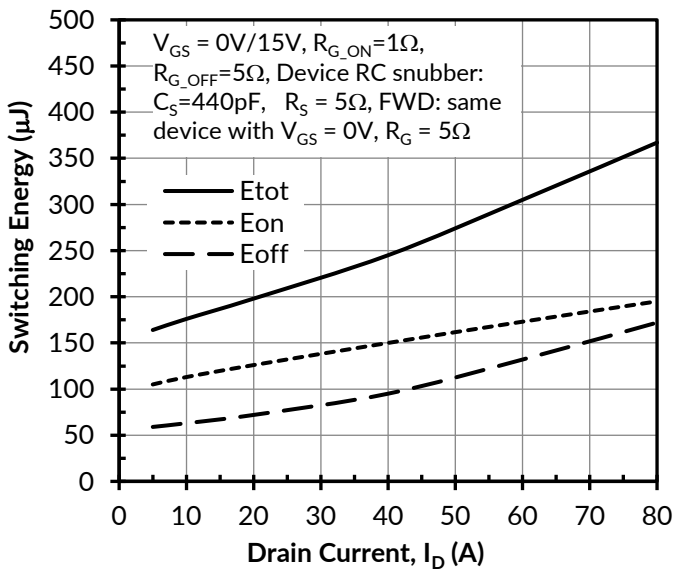


Figure 19. Clamped inductive switching energy vs. drain current at $V_{DS} = 400\text{V}$ and $T_J = 25^\circ\text{C}$

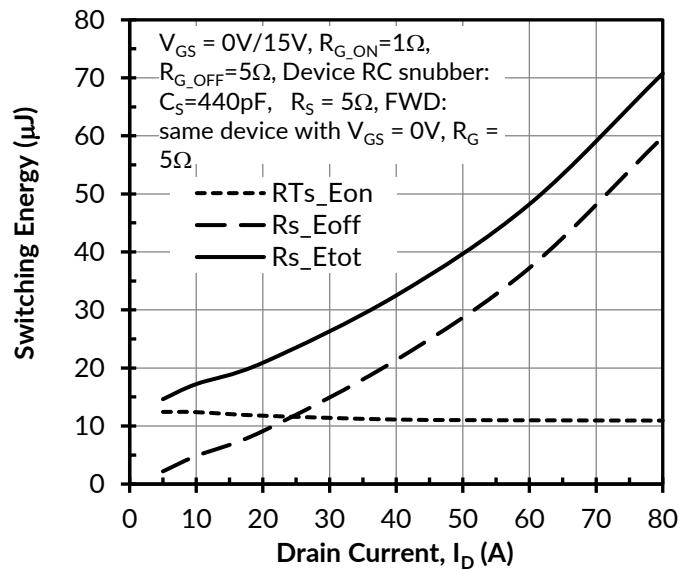


Figure 20. RC snubber energy loss vs. drain current at $V_{DS} = 400\text{V}$ and $T_J = 25^\circ\text{C}$

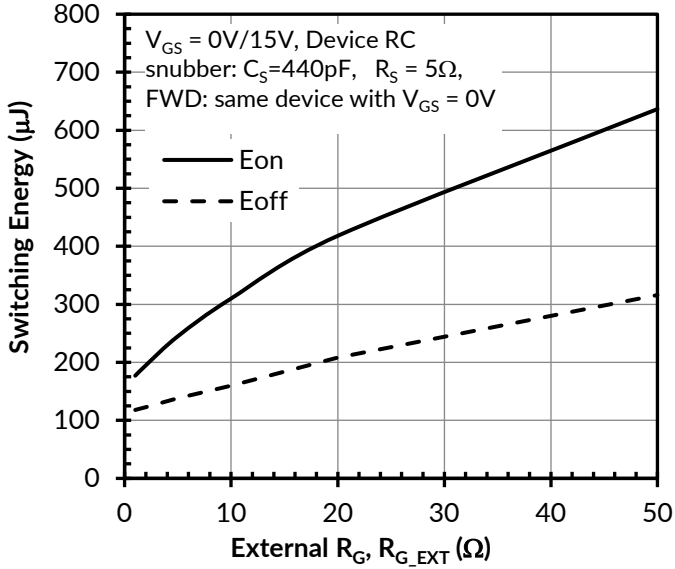


Figure 21. Clamped inductive switching energy vs. $R_{G,EXT}$ at $V_{DS} = 400V$, $I_D = 60A$, and $T_J = 25^\circ C$

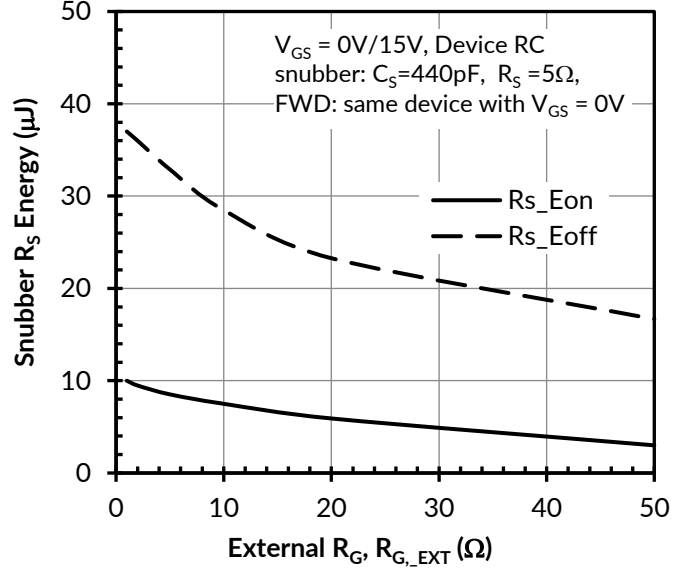


Figure 22. RC snubber energy losses vs. $R_{G,EXT}$ at $V_{DS} = 400V$, $I_D = 60A$, and $T_J = 25^\circ C$

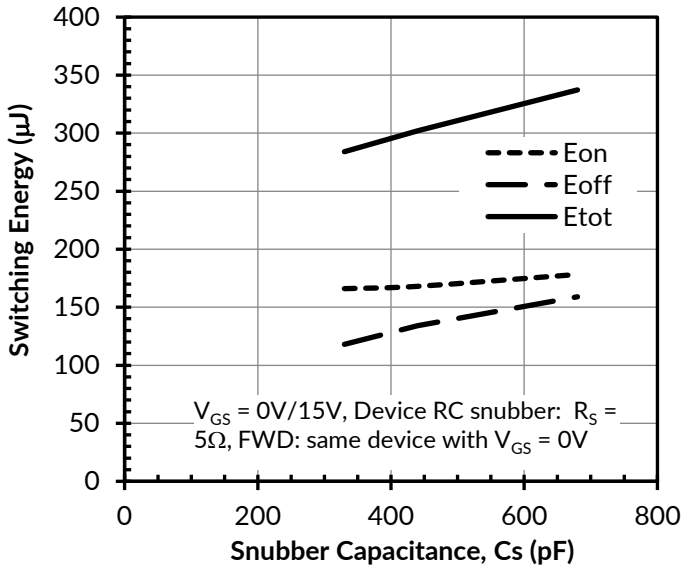


Figure 23. Clamped inductive switching energy vs. Snubber Capacitance C_s at $V_{DS} = 400V$, $I_D = 60A$, and $T_J = 25^\circ C$

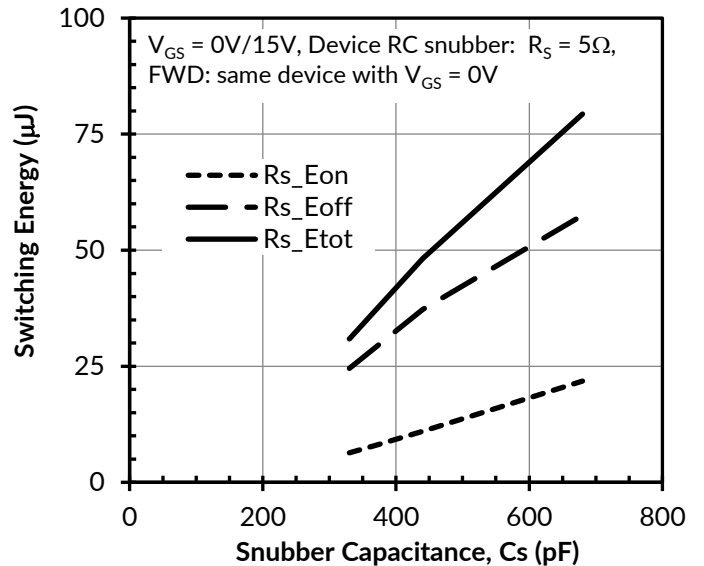


Figure 24. RC snubber energy loss vs. Snubber Capacitance C_s at $V_{DS} = 400V$, $I_D = 60A$, and $T_J = 25^\circ C$

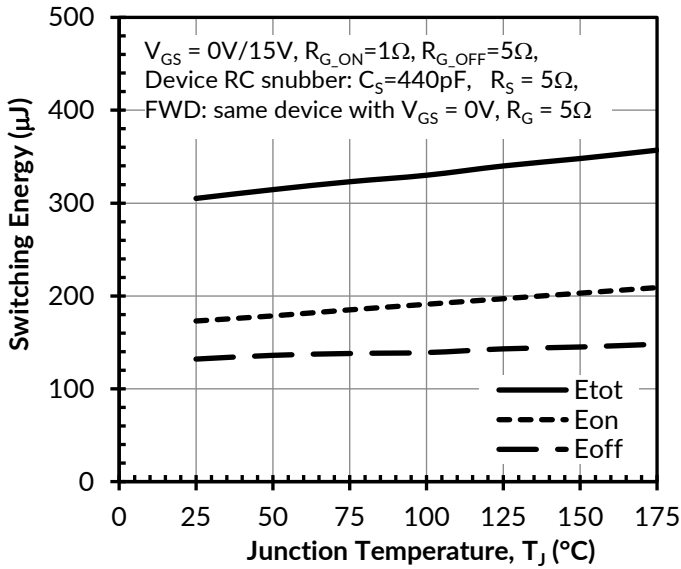


Figure 25. Clamped inductive switching energies vs. junction temperature T_J at $V_{DS} = 400V$, and $I_D = 60A$

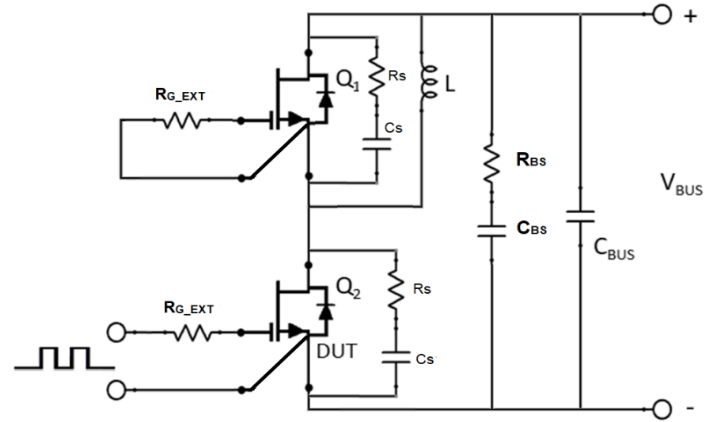
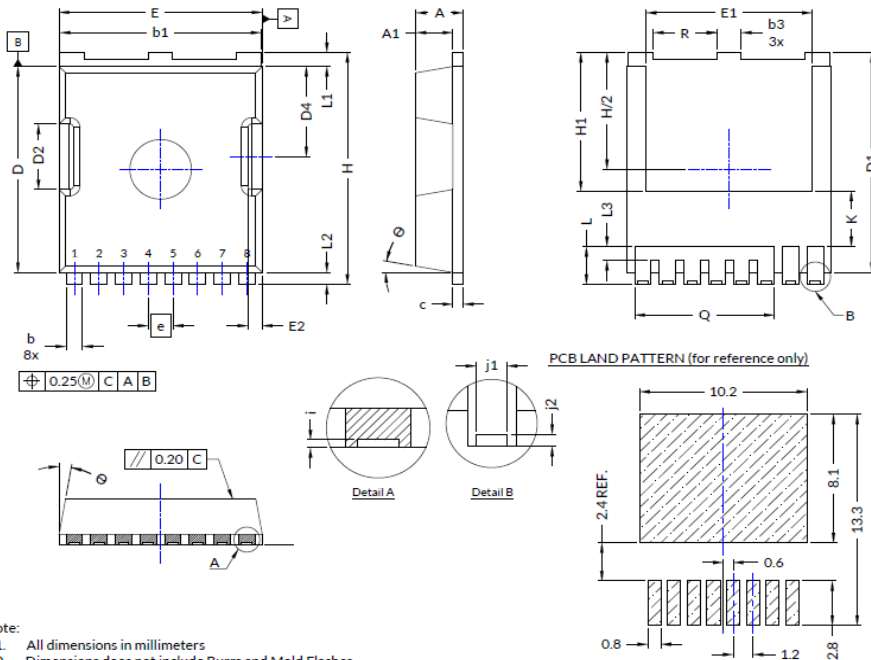


Figure 26. Schematic of the half-bridge mode switching test circuit. Note, device snubber ($R_S = 5\Omega, C_S = 440pF$) and bus RC snubber ($R_{BS} = 1\Omega, C_{BS} = 100nF$) is used to reduce the power loop high frequency oscillations.

Package Outlines



SYMBOL	Value		
	Min	Nom	Max
A	2.15	2.30	2.45
A1	1.80 REF		
b	0.70	0.80	0.90
b1	0.65	0.80	0.95
b3	1.10	1.20	1.30
c	0.40	0.50	0.60
D	10.18	10.38	10.58
D1	10.98	11.08	11.18
D2	3.15	3.30	3.45
D4	4.40	4.55	4.70
E	9.70	9.90	10.10
E1	7.95	8.10	8.25
E2	0.60	0.70	0.80
e	120 BSC		
H	11.48	11.68	11.88
H1	6.80	6.95	7.10
i	0.10 REF		
j1	0.46 REF		
j2	0.20 REF		
K	2.80 REF		
L	1.40	1.90	2.10
L1	0.50	0.70	0.90
L2	0.48	0.60	0.72
L3	0.30	0.70	0.80
Q	6.80 REF		
R	3.00	3.10	3.20
θ	10°		

Note:

- All dimensions in millimeters
- Dimensions does not include Burrs and Mold Flashes
- Dimensions in compliance with JEDEC MO-299B except for backside heatsink exposed pad dimension, E1 and H1

Pin Designations:

- Gate
- Source Kelvin
- 3-8: Source

Applications Information

SiC FETs are enhancement-mode power switches formed by a high-voltage SiC depletion-mode JFET and a low-voltage silicon MOSFET connected in series. The silicon MOSFET serves as the control unit while the SiC JFET provides high voltage blocking in the off state. This combination of devices in a single package provides compatibility with standard gate drivers and offers superior performance in terms of low on-resistance ($R_{DS(on)}$), output capacitance (C_{oss}), gate charge (Q_G), and reverse recovery charge (Q_{rr}) leading to low conduction and switching losses. The SiC FETs also provide excellent reverse conduction capability eliminating the need for an external anti-parallel diode.

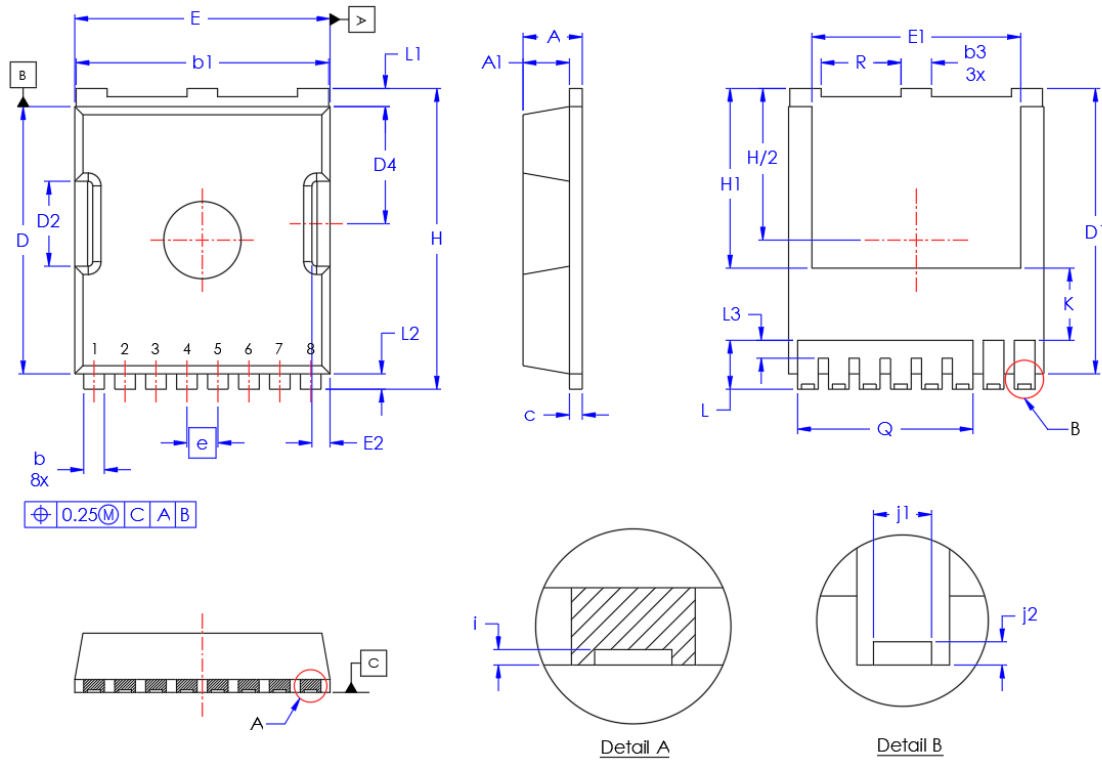
Like other high performance power switches, proper PCB layout design to minimize circuit parasitics is strongly recommended due to the high dv/dt and di/dt rates. An external gate resistor is recommended when the FET is working in the diode mode in order to achieve the optimum reverse recovery performance. For more information on SiC FET operation, see <https://www.qorvo.com/design-hub>.

A snubber circuit with a small $R_{(G)}$, or gate resistor, provides better EMI suppression with higher efficiency compared to using a high $R_{(G)}$ value. There is no extra gate delay time when using the snubber circuitry, and a small $R_{(G)}$ will better control both the turn-off $V_{(DS)}$ peak spike and ringing duration, while a high $R_{(G)}$ will damp the peak spike but result in a longer delay time. In addition, the total switching loss when using a snubber circuit is less than using high $R_{(G)}$, while greatly reducing $E_{(OFF)}$ from mid-to-full load range with only a small increase in $E_{(ON)}$. Efficiency will therefore improve with higher load current. For more information on how a snubber circuit will improve overall system performance, visit the UnitedSiC website at <https://www.qorvo.com/design-hub>.

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PACKAGE OUTLINE



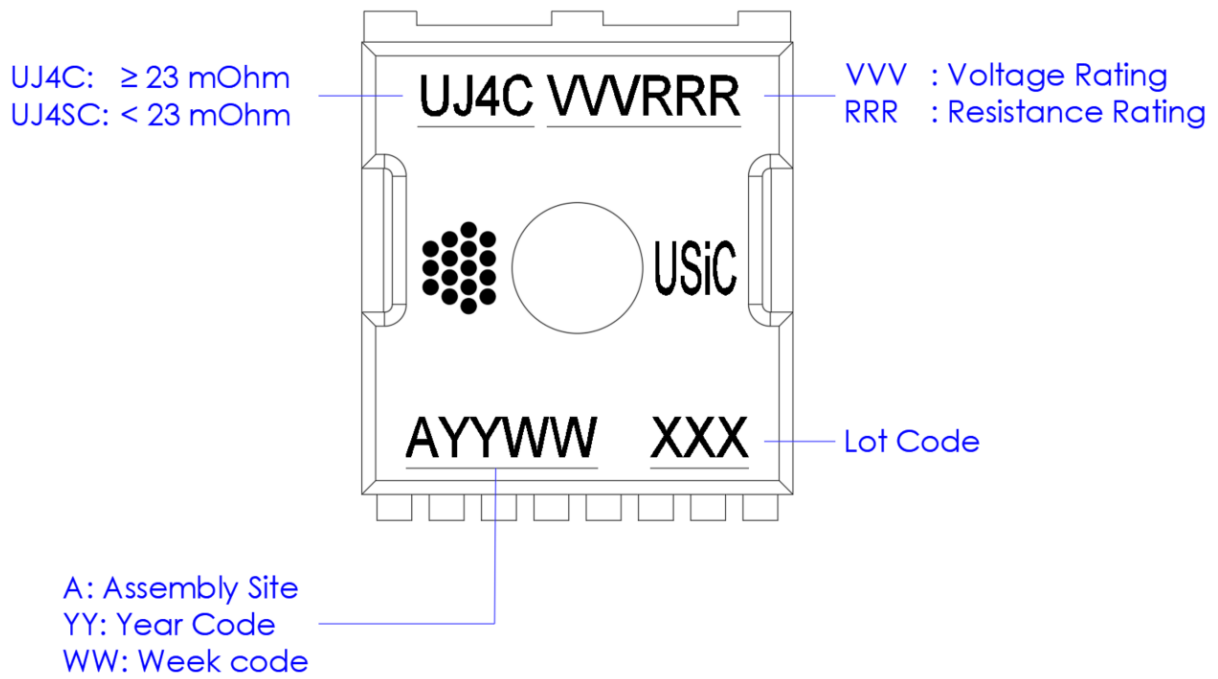
⊕ 0.25(M) C A B

SYMBOL	TO-LL Value	
	Min	Max
A	2.15	2.45
A1	1.80 REF	
b	0.65	0.90
b1	9.65	9.95
b3	1.10	1.30
c	0.40	0.60
D	10.18	10.58
D1	10.88	11.28
D2	3.15	3.45
D4	4.40	4.70
E	9.70	10.10
E1	7.95	8.25
E2	0.60	0.80
e	1.20 BSC	
H	11.48	11.88
H1	6.80	7.10
i	0.10 REF	
j1	0.46 REF	
j2	0.20 REF	
K	2.80 REF	
L	1.40	2.10
L1	0.50	0.90
L2	0.48	0.72
L3	0.30	0.80
Q	6.80 REF	
R	3.00	3.20

Note:

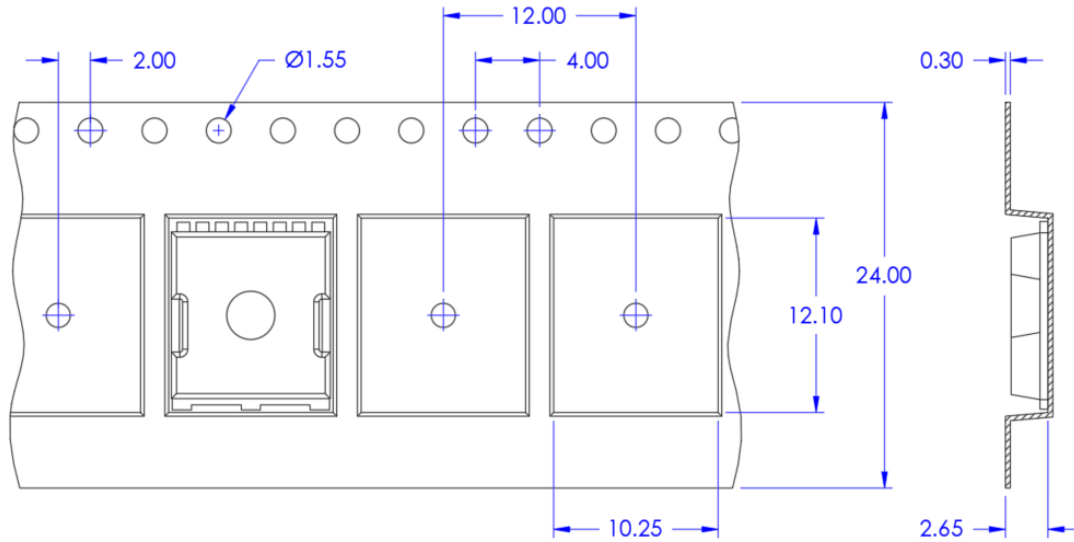
1. All dimensions in millimeters
2. Dimensions does not include Burrs and Mold Flashes

PART MARKING

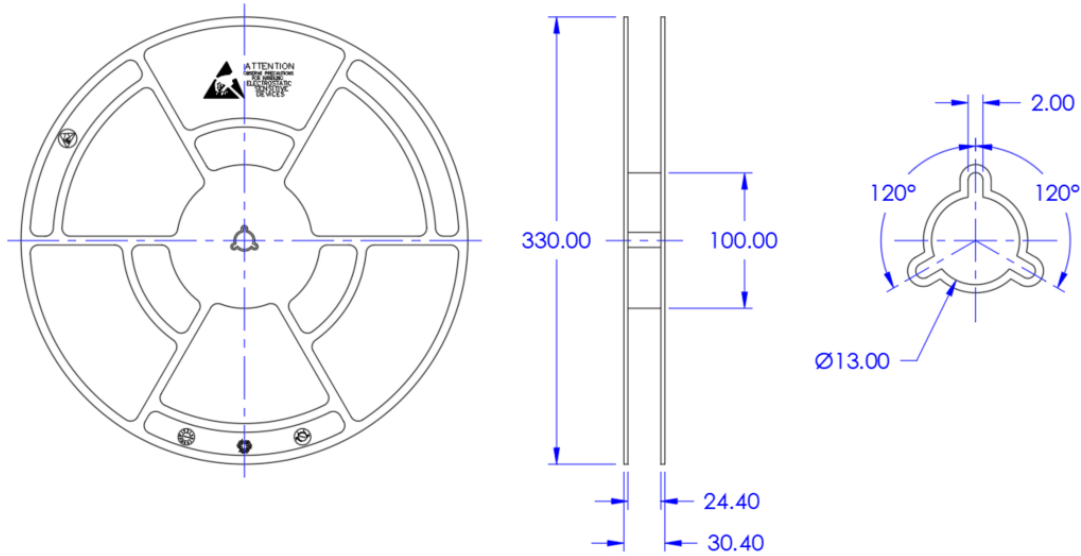


PACKING TYPE


Carrier Tape



Reel



All dimensions in millimeters
Quantity per Reel: 2000 units

	TOLL PACKAGE OUTLINE, PART MARKING, TAPE AND REEL SPECIFICATION	Page 4 of 4
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REVISION HISTORY

Revision	Create Date (mm/dd/yyyy)	Description of Change	Initiator of Change
A	10/13/2023	Initial Production Release	Glenn Galang
B	01/31/2024	Corrected device orientation inside carrier tape pocket (Page 3)	Glenn Galang

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